

# Search Notes



Application No.

09/816,210

Examiner

Tan Dean D. Nguyen

Applicant(s)

COSTIN ET AL.

Art Unit

3629

## SEARCHED

Class	Subclass	Date	Examiner
705	1	7/12/04	DN
	7		
	8		
	10		
	14		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Classified: 705/1	7/14/04	DN
US Patent/PG		
Foreign		
NPL 1) Ftext <sup>1</sup>		
2) Ftext <sup>2</sup>		
3) NFtext		